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<b>Notice of References Cited</b>	Application/Control No. 09/794,209		Applicant(s)/Patent Under Reexamination WAYAMA ET AL.	
	Examiner John T. Kwon		Art Unit 3747	Page 1 of 1

### U.S. PATENT DOCUMENTS

*	Country Code	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,835,878 A	11-1998	Saito et al.	701/94
	B	US-6,491,019 B1	12-2002	Apel, Peter	123/337
	C	US-6,407,543 B1	06-2002	Hagio et al.	324/207.25
	D	US-6,483,296 B1	11-2002	Hamaoka et al.	324/207.25
	E	US-			
	F	US-			
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	Examiner John T. Kwon	Art Unit 3754	Page 1 of 1

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,823,165	10-1998	Sato et al.	123/361
	B	US-6,067,961	05-2000	Kato, Hideki	123/399
	C	US-6,092,506	07-2000	Takagi et al.	123/399
	D	US-6,240,899	06-2001	Yamada et al.	123/396
	E	US-6,318,338	11-2001	Kawamura et al.	123/399
	F	US-6,332,451	12-2001	Sato et al.	123/399
	G	US-6,349,701	02-2002	Sakurai et al.	123/361
	H	US-6,390,062	05-2002	Saito et al.	123/361
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	K	US-			
	L	US-			
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FORM PTO-1449

U.S. Department of Commerce  
Patent & Trademark OfficeAttorney Docket No.  
381AS/49700Serial No.  
09/794,209

Applicant: Eisuke WAYAMA, et al.

Filing Date  
February 28, 2001

Group

INFORMATION DISCLOSURE  
STATEMENT

(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date (if appropriate)
	AA	5672818	09/1997	Schaefer, et al.			
	AB						
	AC						
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Examiner Initial		Document Number	Date	Name	Class	Sub- Class	TRANSLATION	
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<i>OK</i>	AK	11-211410	08/1999	Japan				
<i>J</i>	AL	1024267	08/2000	Europe				
	AM	1028239	08/2000	Europe				
	AN	19903490	08/2000	Germany				
<i>OK</i>	AO	19547408	07/1997	Germany				
	AP							

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AQ	Search Report					
	AR						
	AS						

EXAMINER

John Kwon  
Primary Examiner

DATE CONSIDERED

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Attorney Docket No.  
381AS/49700

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**U.S. PATENT DOCUMENTS**

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
<i>[Signature]</i>	AA	4392375	07/1983	Eguchi, et al.			
<i>[Signature]</i>	AB	5528139	06/1996	Oudet, et al.			
<i>[Signature]</i>	AC	6448762	09/2002	Kono, et al.			
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		Applicants <b>EISUKE WAYAMA ET AL.</b>	
		Filing Date <b>FEBRUARY 28, 2001</b>	Group Art Unit:

JCS 86 U.S. PTO  
 027794209

U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
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	AB						
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FOREIGN PATENT DOCUMENTS							
		Document	Date	Country	Class	Sub-class	Translation Yes   No
	AF	JP 9-32588	2-04-97	Japan	1	1	abstract
	AG	JP 2845884	10-30-98	Japan	1	1	abstract
	AH						
	AI						
	AJ						
AK							
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EXAMINER <div style="text-align: center;"> <b>John Kwon</b>  <b>Primary Examiner</b> </div>	DATE CONSIDERED <div style="text-align: center; font-size: 1.2em;"> <b>9/27/02</b> </div>
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